



Search for exotic production of top quarks with same-sign leptons

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Introduction

- Search for exotic **top** quark production is theoretically motivated
 - Top mass, radiative Higgs correction, Higgs stability ...
- **Same-sign leptons** can be the signature of many exotic top production:
 - Same-sign tops $t\bar{t}$ or $t\bar{t}$, $\geq 3t$, $t\bar{t}$ +extra bosons
 - Leading to $l^\pm l^\pm(l) + bjets + jets + Et_{miss}$
 - Low background from the standard model
- Today, I will present **4 analyses** from **ATLAS** and **CMS**:
 - Search for top quark partners with charge 5/3 at 13TeV (**CMS T5/3**): [Link](#)
 - Search for new physics in same-sign dilepton events at 13TeV (**CMS Susy**): [link](#)
 - Search for supersymmetry at 13TeV with jets and two same-sign leptons or three leptons (**ATLAS Susy**): [link](#)
 - Analysis of events with b-jets and a pair of leptons of the same charge at 8TeV (**ATLAS VLQ**): [link](#)
 - Will soon be published with 13TeV data

BSM Models (1): VLQ and SUSY

- Vector Like Quark (VLQ) signatures: $t\bar{t} + X$

- Double production: TT, BB or $T_{5/3}T_{5/3}$

- Limit in m_Q and $\text{Br}(Q \rightarrow qV)$

- $T \rightarrow Zt, Ht$ or Wb

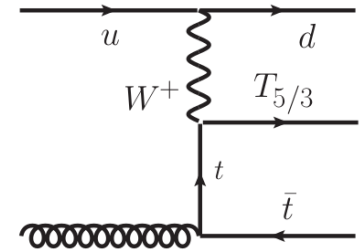
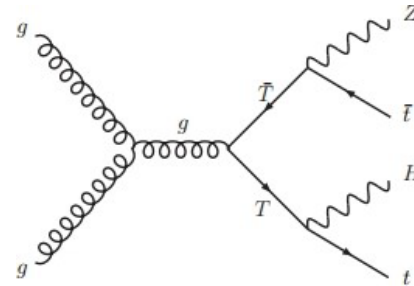
- $B \rightarrow Zb, Hb$ or Wt

- $T_{5/3} \rightarrow Wt$

- Single production:

- Limit in m_Q and coupling C

- Large jet activities (H_T)



- Supersymmetric signature: $t\bar{t} + X + E_{miss}^T$

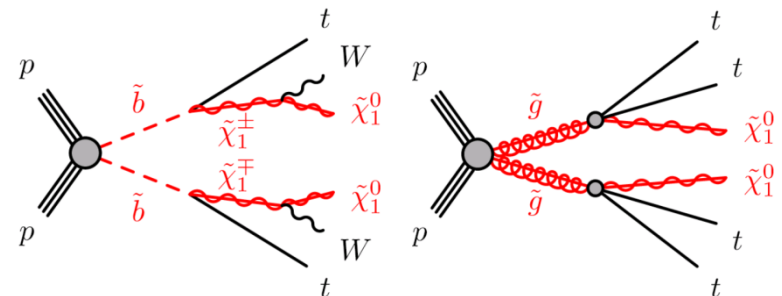
- Light gluino and 3rd generation squark motivated by naturalness

- Large production of $\tilde{g}\tilde{g}, \tilde{t}\tilde{t}$ and $\tilde{b}\tilde{b}$

- And large $\text{Br}(\tilde{g} \rightarrow \tilde{t}t)$

- Two signals producing top quarks:

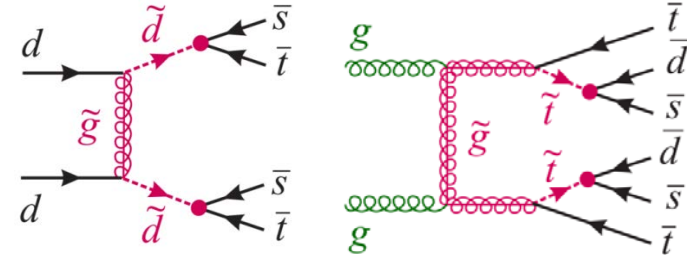
- Large MET from neutralino



BSM Models (2): RPV and 4tops

- Baryonic number violation search: *same-sign tops*

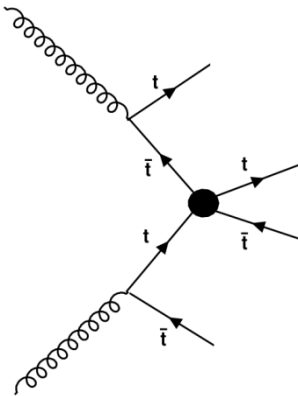
- Low energy constraint (proton stability) implies $\Delta B=2$ processes involving top quarks
- Possible realization with **R-parity violation SUSY**:
- No neutralino (low MET) but high jet activities



- Four tops signature: $t\bar{t}t\bar{t}$

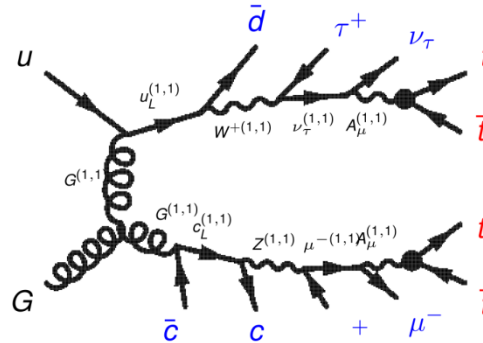
- Effective theory:

$$\mathcal{L}_{4t} = \frac{C_{4t}}{\Lambda^2} (\bar{t}_R \gamma^\mu t_R) (\bar{t}_R \gamma_\mu t_R)$$

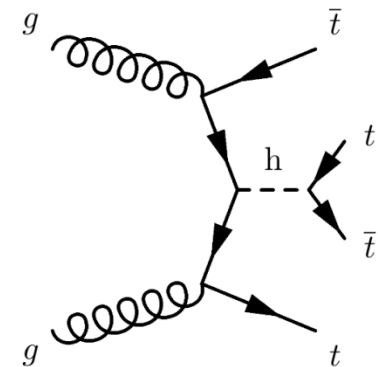


- Extra-dimension

- Universal Extra Dimension



- 2HDM type-II



Selections:

- All analyses require **same-sign leptons** or **3 leptons**
 - + additional cuts on jet activities, Number of jets/b-jets, MET...
- General feature:
 - **CMS T5/3** and **ATLAS VLQ** cuts optimized for the search of **energetic** tops
 - High jet activities cut and high lepton Pt (25-30GeV)
 - **CMS Susy** and **ATLAS Susy** cuts optimized for **massive** neutralinos (compressed scenario):
 - High MET cut and low lepton Pt (10GeV)
 - Additional cuts are also required on N_{bjets} , N_{jets} , $M_T^{\min}$, M_{eff} , $N_{constuents}$...
- Signal region:
 - **CMS T5/3** and **ATLAS Susy** analysis use **inclusive** signal regions
 - **CMS Susy** and **ATLAS VLQ** analysis use **several** signal regions **split** in different kinematic cut requirements

ATLAS Susy

Table 1: Summary of the event selection criteria for the signal regions (see text for details).

Signal region	N_{lept}^{signal}	N_{b-jets}^{20}	N_{jets}^{50}	E_T^{miss} [GeV]	m_{eff} [GeV]
SR1b	≥ 2	≥ 1	≥ 4	> 150	> 550
SR3b	≥ 2	≥ 3	-	> 125	> 650

CMS T5/3

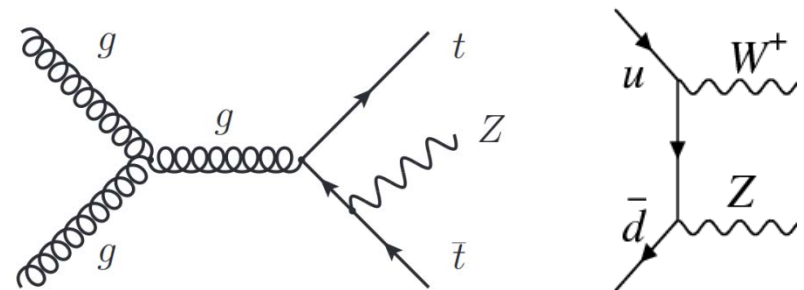
N_{lep}	HT	MeT	$N_{lep+jet}$
≥ 2	> 900 GeV	> 0 GeV	≥ 5

- More detailed signal region description in [backup](#)

Background composition

1) True same-sign/three leptons

- From Standard Model
- Dominant: $t\bar{t} + V$ and VV
- Simulated by *Monte-Carlo* method



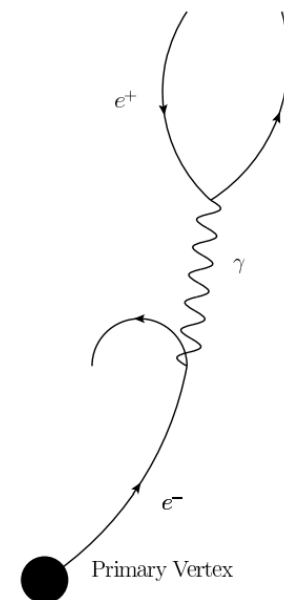
2) Fake/non-prompt lepton

- Light jet reconstructed as lepton
- Lepton coming from heavy-flavor jet
- Estimated by *data-driven* method

3) Charge mis-identification

- Detector effect
- Negligible for muon
- Two sources:
 - **Tracker** charge reconstruction efficiency
 - Electron from **photon conversion**
- Estimated by *data-driven* method

Photon conversion:



Fake/non-prompt lepton estimation method

- **Lepton definition:**

- The fake estimation methods rely on the definition of lepton criteria:
loose and **tight** criteria
 - For electrons, the identification and isolation are used
 - For muons, the isolation criteria is used

- **Matrix method:**

$$\begin{pmatrix} N_t \\ N_{\bar{t}} \end{pmatrix} = M \begin{pmatrix} N_{real} \\ N_{fake} \end{pmatrix} \quad M = \begin{pmatrix} \epsilon_r & \epsilon_f \\ (1 - \epsilon_r) & (1 - \epsilon_f) \end{pmatrix} \quad \begin{matrix} t=\text{tight} \\ \bar{t}=\text{loose but not tight} \end{matrix}$$

- N_{fake} is estimated by weighting N_t and $N_{\bar{t}}$ with the elements of M^{-1}
- Generalized for 2 and 3 leptons

- **Tight-to-loose method:**

- ϵ_{TL} : probability that a **fake** loose lepton is tagged as **tight** ($\sim \epsilon_f$)
- N_{fake} estimated by
 - selecting events with ≥ 1 loose but not tight lepton
 - Weight them by $\epsilon_{TL}/(1 - \epsilon_{TL})$
- Equivalent to Matrix Method by considering that $\epsilon_r \approx 1$

Real and fake efficiency measurement and systematic

- **Efficiency estimation:**
 - ϵ_r estimated on enriched **real** lepton region
 - *Single lepton* region: High MET and MT (W+jets)
 - *Dilepton* region: Z mass window (Z $\rightarrow$ ll)
 - ϵ_f estimated on enriched **fake** lepton region
 - *Single lepton* region: Low MET and MT (multijet background)
 - *SS Dilepton* region: Tight muon + 1 loose lepton (V+jets and ttbar)
 - Real lepton contribution are subtracted from fake region
 - Usually parameterized in **Pt** and **|\eta|** of the leptons
 - And sometimes other parameters like triggers, N_{bjets} ... etc
- Systematic uncertainties: around **35-60%**
 - Fake composition (light jet, c-jets, b-jets) can be different in other regions
 - Alternative control region or truth matching studies
 - Other kinematic dependences
 - Statistical uncertainty from fake/real lepton control regions
 - Real lepton bkg removal in fake region
 - Closure tests or comparison with other methods

Charge mis-identification background

- Based on the **charge flip rates ϵ**
 - Defined as the probability of one electron to have its charge mis-identified
 - **Parameterized** on P_t and $|\eta|$
- Charge mis-identification bkg estimated by **weighting opposite-sign** dielectron events by:

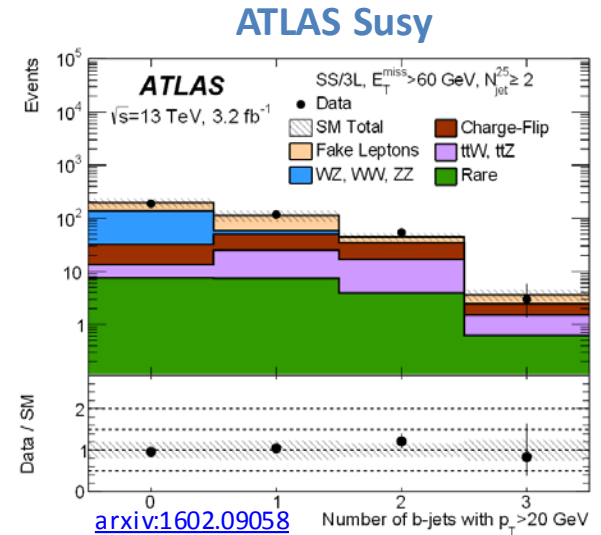
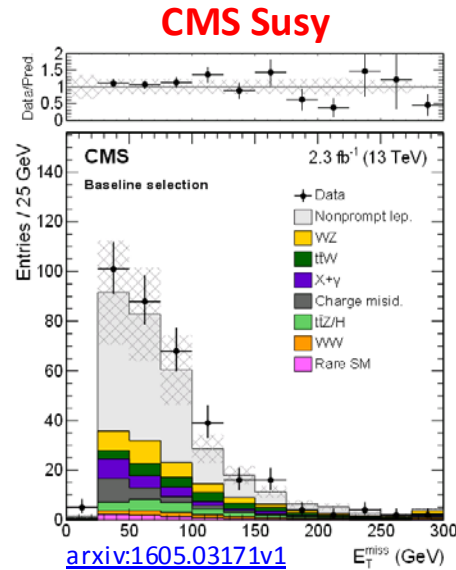
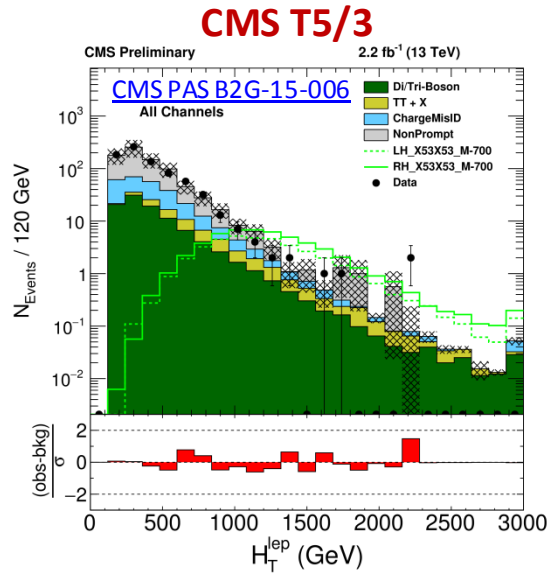
$$w = \frac{\epsilon_1(1 - \epsilon_2) + \epsilon_2(1 - \epsilon_1)}{(1 - \epsilon_1)(1 - \epsilon_2) + \epsilon_1\epsilon_2}$$

ϵ_1 charge flip rate of 1st electron
 ϵ_2 charge flip rate of 2nd electron

- Charge flip rate estimation on enriched $pp \rightarrow Z \rightarrow ee$ data events:
 - $m_{ee} \in [m_Z - X, m_Z + X]$
 - Count the number of e^+e^- and same-sign $e^\pm e^\pm$
 - Charge flip rates estimated by Likelihood minimization $\mathcal{L}(\epsilon|N, N_{ss})$
- Systematic uncertainties: around **20-30%**
 - Statistical uncertainty from likelihood minimization
 - Kinematic dependences
 - Closure tests on MC V+jets samples
 - Invariant mass cuts variations

Validation plots

- Validation plots at pre-selection level:

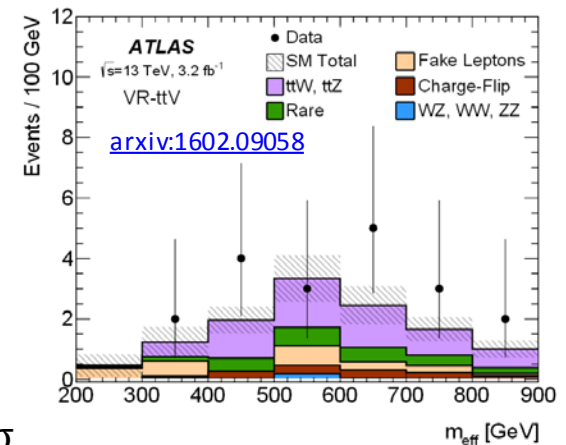


- Control regions **ATLAS Susy**:

	VR-WW	VR-WZ	VR-ttV	VR-ttZ
Observed events	4	82	19	14
Total background events	3.4 ± 0.8	98 ± 15	12.1 ± 2.7	9.7 ± 2.5
Fake/non-prompt leptons	0.6 ± 0.5	8 ± 6	2.1 ± 1.4	0.6 ± 1.0
Charge-flip	0.26 ± 0.05	—	1.14 ± 0.15	—
$t\bar{t}W$	0.05 ± 0.03	0.25 ± 0.09	2.4 ± 0.8	0.10 ± 0.03
$t\bar{t}Z$	0.02 ± 0.01	0.72 ± 0.26	3.9 ± 1.3	6.3 ± 2.1
WZ	1.0 ± 0.4	78 ± 13	0.19 ± 0.10	1.2 ± 0.4
$W^\pm W^\pm jj$	1.3 ± 0.5	—	0.02 ± 0.03	—
ZZ	0.02 ± 0.01	8.2 ± 2.8	0.12 ± 0.15	0.30 ± 0.19
Rare	0.10 ± 0.05	2.8 ± 1.4	2.3 ± 1.2	1.1 ± 0.6

[arxiv:1602.09058](https://arxiv.org/abs/1602.09058)

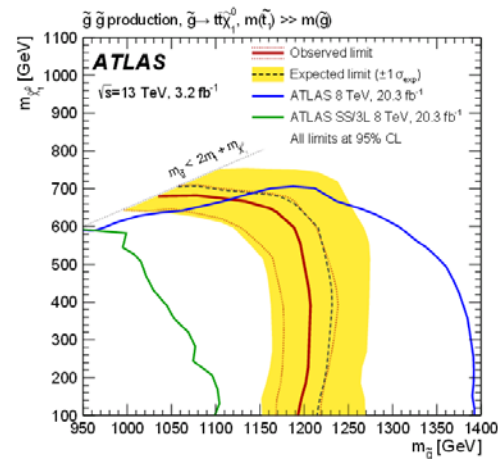
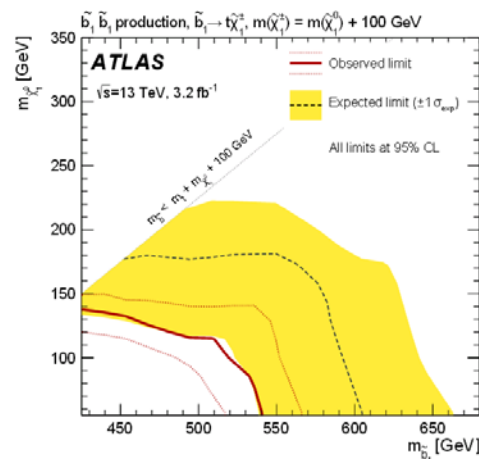
Deviation of 1.5σ



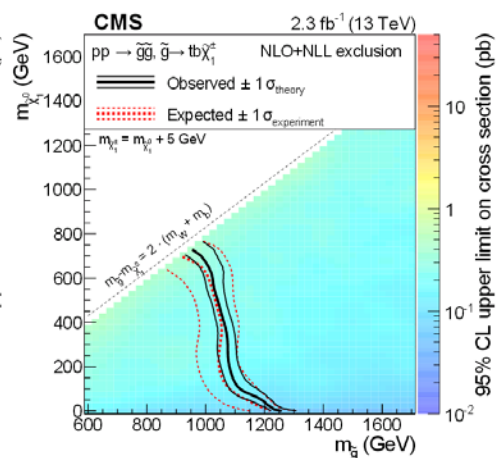
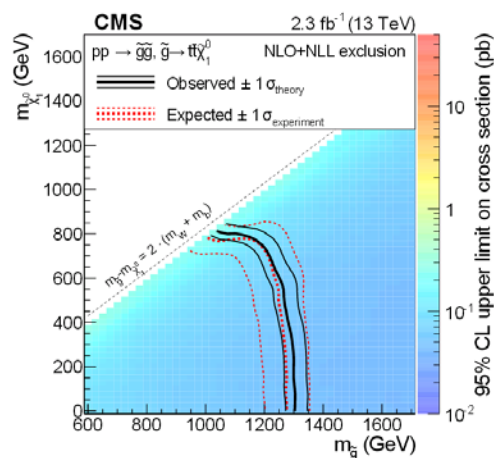
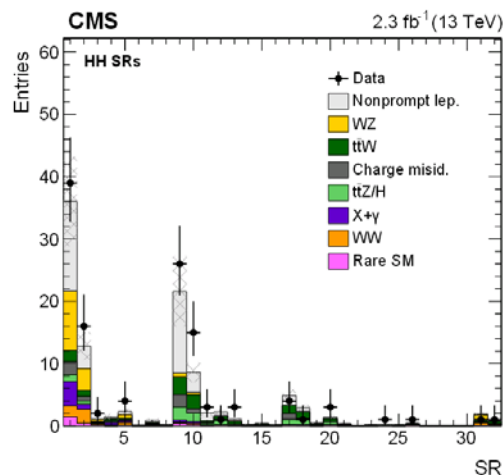
Results: SUSY

• ATLAS Susy

	SR1b	SR3b
Observed events	7	1
Total background events $p(s=0)$	4.5 ± 1.0 0.15	0.80 ± 0.25 0.36
Fake/non-prompt leptons	0.8 ± 0.8	0.13 ± 0.17
Charge-flip	0.60 ± 0.12	0.19 ± 0.06
$t\bar{t}W$	1.1 ± 0.4	0.10 ± 0.05
$t\bar{t}Z$	0.92 ± 0.31	0.14 ± 0.06
WZ	0.18 ± 0.11	< 0.02
$W^\pm W^\pm jj$	0.03 ± 0.02	< 0.01
ZZ	< 0.03	< 0.03
Rare	0.8 ± 0.4	0.24 ± 0.14



• CMS Susy



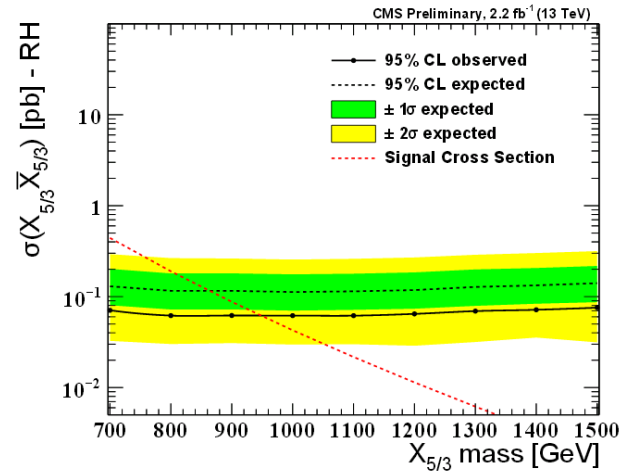
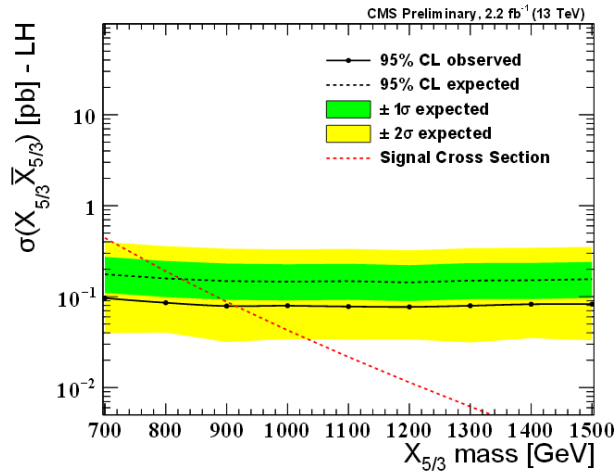
— Better sensitivity for CMS because of the exclusives SRs

Results: T5/3

- CMS T5/3**

[CMS PAS B2G-15-006](#)

Channel	PSS MC	NonPrompt	ChargeMisID	Total Background	800 GeV $X_{5/3}$	Observed
Di-electron	2.41 ± 0.29	2.16 ± 1.91	1.90 ± 0.60	6.47 ± 2.02	4.38	7
Electron-Muon	2.98 ± 0.36	5.20 ± 3.21	0.54 ± 0.18	8.72 ± 3.24	9.14	3
Di-muon	0.70 ± 0.12	2.09 ± 1.69	0.00 ± 0.00	2.80 ± 1.70	3.55	1
All	6.09 ± 0.67	9.45 ± 5.49	2.44 ± 0.76	17.98 ± 5.58	17.06	11



- 100-200GeV of improvement compared to 8TeV
- Results combined with 1 lepton analysis

Conclusion

- Same-sign lepton is a **well-motivated** signature for the search of new physics involving top quarks
 - Supersymmetry, vector-like quarks ...
- **Different** selection strategy for each analysis
- Imply to use sophisticated **data-driven technique** to estimate fake and charge mis-identification background
 - Handled in a different way for each analysis
- **No deviation** found at 13TeV
 - Exclusion limits set for supersymmetric and T5/3 models
- **New results** will be published soon:
 - **ATLAS VLQ** search on going
 - And future 2016 data !
- I hope we will find surprising excess 😊



Backup

Selection: Susy

ATLAS Susy

Table 1: Summary of the event selection criteria for the signal regions (see text for details).

Signal region	$N_{\text{lept}}^{\text{signal}}$	$N_{b\text{-jets}}^{20}$	N_{jets}^{50}	$E_{\text{T}}^{\text{miss}}$ [GeV]	m_{eff} [GeV]
SR0b3j	≥ 3	$= 0$	≥ 3	> 200	> 550
SR0b5j	≥ 2	$= 0$	≥ 5	> 125	> 650
SR1b	≥ 2	≥ 1	≥ 4	> 150	> 550
SR3b	≥ 2	≥ 3	-	> 125	> 650

CMS Susy

Table 2: SR definitions for the HH selection. The notation (*) indicates that, in order to avoid overlaps with SR31, an upper bound $E_{\text{T}}^{\text{miss}} < 300$ GeV is used for regions with $H_{\text{T}} > 300$ GeV.

N_b	M_T^{min} (GeV)	E_T^{miss} (GeV)	N_{jet}	$H_T < 300$ GeV	$H_T \in [300, 1125]$ GeV	$H_T > 1125$ GeV	
0	< 120	50 – 200	2-4	SR1	SR2	SR32	
			> 5		SR4		
		> 200(*)	2-4	SR3	SR5		
			> 5		SR6		
	> 120	50 – 200	2-4	SR3	SR7		
			> 5		SR8		
		> 200(*)	2-4	> 5			
			> 5				
1	< 120	50 – 200	2-4	SR9	SR10		
			> 5		SR12		
		> 200(*)	2-4	SR11	SR13		
			> 5		SR14		
	> 120	50 – 200	2-4		SR11		SR15
			> 5				SR16
		> 200(*)	2-4	> 5			
			> 5				
2	< 120	50 – 200	2-4	SR17	SR18		
			> 5		SR20		
		> 200(*)	2-4	SR19	SR21		
			> 5		SR22		
	> 120	50 – 200	2-4		SR19		SR23
			> 5				SR24
		> 200(*)	2-4	> 5			
			> 5				
> 3	< 120	50 – 200	> 2	SR25	SR26		
		> 200(*)	> 2	SR27	SR28		
	> 120	> 50(*)	> 2	SR29	SR30		
		Inclusive	Inclusive	> 300	> 2		—

Table 3: SR definitions for the HL selection. The notation (*) indicates that, in order to avoid overlaps with SR25, an upper bound $E_{\text{T}}^{\text{miss}} < 300$ GeV is used for regions with $H_{\text{T}} > 300$ GeV.

N_b	$M_T^{\min}$ (GeV)	E_T^{miss} (GeV)	N_{jet}	$H_T < 300$ GeV	$H_T \in [300, 1125]$ GeV	$H_T > 1125$ GeV	
0	< 120	50 – 200	2-4	SR1	SR2	SR26	
			> 5		SR4		
		> 200(*)	2-4	SR3	SR5		
			> 5		SR6		
1	< 120	50 – 200	2-4	SR7	SR8		
			> 5		SR10		
		> 200(*)	2-4	SR9	SR11		
			> 5		SR12		
2	< 120	50 – 200	2-4	SR13	SR14		
			> 5		SR16		
		> 200(*)	2-4	SR15	SR17		
			> 5		SR18		
> 3	< 120	50 – 200	> 2	SR19	SR20		
		> 200(*)	> 2	SR21	SR22		
Inclusive	> 120	> 50(*)	> 2	SR23	SR24		
Inclusive	Inclusive	> 300	> 2	—	SR25		

Table 4: SR definitions for the LL selection. All SRs in this category require $N_{\text{jet}} \geq 2$.

N_b	$M_{\text{T}}^{\text{min}}$ (GeV)	H_{T} (GeV)	$E_{\text{T}}^{\text{miss}} \in [50, 200]$ GeV	$E_{\text{T}}^{\text{miss}} > 200$ GeV
0	< 120	> 300	SR1	SR2
1			SR3	SR4
2			SR5	SR6
≥ 3			SR7	
Inclusive	> 120		SR8	

Selection VLQ

ATLAS VLQ

Definition			Name	
$e^{\pm}e^{\pm} + e^{\pm}\mu^{\pm} + \mu^{\pm}\mu^{\pm} + eee + ee\mu + e\mu\mu + \mu\mu\mu, N_j \geq 2$				
$400 < H_{\text{T}} < 700 \text{ GeV}$	$N_b = 1$	$E_{\text{T}}^{\text{miss}} > 40 \text{ GeV}$	SRVLQ0	
	$N_b = 2$		SRVLQ1	SR4t0
	$N_b \geq 3$		SRVLQ2	SR4t1
$H_{\text{T}} \geq 700 \text{ GeV}$	$N_b = 1$	$40 < E_{\text{T}}^{\text{miss}} < 100 \text{ GeV}$	SRVLQ3	
		$E_{\text{T}}^{\text{miss}} \geq 100 \text{ GeV}$	SRVLQ4	
	$N_b = 2$	$40 < E_{\text{T}}^{\text{miss}} < 100 \text{ GeV}$	SRVLQ5	SR4t2
		$E_{\text{T}}^{\text{miss}} \geq 100 \text{ GeV}$	SRVLQ6	SR4t3
	$N_b \geq 3$	$E_{\text{T}}^{\text{miss}} > 40 \text{ GeV}$	SRVLQ7	SR4t4

- At least two isolated same-sign leptons as defined above with $p_T > 30 \text{ GeV}$. Between each lepton and every top-quark jet, we require $\Delta R > 0.8$.
- Dilepton Z-boson veto: $M(ee) < 76 \text{ GeV}$ or $M(ee) > 106 \text{ GeV}$. This selection applies only to the dielectron channel. If the muon charge is mismeasured, its momentum will also be mismeasured so a selected muon pair from a Z boson will not fall within this invariant mass range.
- Trilepton Z-boson veto: $M(\ell\ell) < 76 \text{ GeV}$ or $M(\ell\ell) > 106 \text{ GeV}$ where $M(\ell\ell)$ is the invariant mass of either one of the selected leptons and any other same flavor opposite-sign lepton in the event with $p_T > 15 \text{ GeV}$ that satisfies the loose lepton criteria.
- $N_c \geq 7$, where N_c is the number of constituents identified in the event. For the purpose of this selection, each AK5 jet and each lepton counts as one constituent. Since a W-boson jet is assumed to correspond to a W boson, each such jet counts as two constituents, corresponding to the W-boson decay products. Likewise, each top-quark jet represents a top quark and counts as three constituents.
- $H_T > 900 \text{ GeV}$, where H_T is the scalar sum of the p_T of all selected jets and leptons in the event.

CMS T5/3

Fake/non-prompt lepton: method

	ATLAS Susy	ATLAS VLQ	CMS Susy	CMS T5/3
Method	Matrix Method	Matrix Method	Tight-to-loose	Matrix Method
Fake lepton region	Dilepton: 1 μ +1lepton	Single lepton: Low MT, ETmiss	Single lepton: Low MT, ETmiss	Single lepton: Low MT, ETmiss
Real lepton region	Dilepton: Z mass window	Single lepton: High MT, ETmiss		Dilepton: Z mass window
Parametrization	Pt / $ \eta $	Pt / $ \eta $ / N _{bjet} / trigger	Pt / $ \eta $ / trigger	No param
Validation	Alternative fake estimate	Closure tests	Alternative rate measurement	Closure tests

Charge mis-identification: Method

- Based on the **Charge flip rates ϵ**
 - Defined as the probability of one electron to have its charge mis-identified
 - Parameterized** on Pt and $|\eta|$
- Then, assuming a **true** number of **opposite-sign** dielectron events, we have:

$$N_{SS}^{reco} = N_{OS}^{true} (\epsilon_1(1 - \epsilon_2) + \epsilon_2(1 - \epsilon_1))$$

ϵ_1 charge flip rate of 1st electron

$$N_{OS}^{reco} = N_{OS}^{true} ((1 - \epsilon_1)(1 - \epsilon_2) + \epsilon_1\epsilon_2)$$

ϵ_2 charge flip rate of 2nd electron

- N_{SS}^{reco} can be estimated by weighting N_{OS}^{reco} by:

$$w = \frac{\epsilon_1(1 - \epsilon_2) + \epsilon_2(1 - \epsilon_1)}{(1 - \epsilon_1)(1 - \epsilon_2) + \epsilon_1\epsilon_2}$$

- Charge flip rate estimation on enriched $pp \rightarrow Z \rightarrow ee$ data events:
 - $m_{ee} \in [m_Z - X, m_Z + X]$
 - ex: $X=10\text{GeV}$ in **CMS T5/3**
 - Count the number of e^+e^- and same-sign $e^\pm e^\pm$
 - Charge flip rates estimated by Likelihood minimization

$$\mathcal{L}(\epsilon|N, N_{SS}) = \text{Poisson}(N_{SS}|N, \epsilon)$$

